

# Qualification Results Summary for ADuM2200W/ADuM2201W Die Revision and Data Sheet Change (SOIC\_W)

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	<b>8x77 1x45</b>	<b>Pass</b>
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	<b>9x77</b>	<b>Pass</b>
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	<b>9x77</b>	<b>Pass</b>
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	<b>9x77</b>	<b>Pass</b>
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	<b>9x45</b>	<b>Pass</b>
Latch-Up	JEDEC <i>JESD78</i>	<b>1x9</b>	<b>Pass ±200mA @ +8.25V</b>
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	<b>1x18</b>	<b>Pass ±4000V</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	<b>1x18</b>	<b>Pass ±1250V</b>

\*Preconditioned per JEDEC/IPC J-STD-020